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IAP9 Rec'd PCT/PTO 01 SEP 2006

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

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| INFORMATION DISCLOSURE STATEMENT | | Docket Number 10191/4351 |
| Application Number To Be Assigned | Filing Date Herewith | Examiner To Be Assigned |
| Invention Title INTERFEROMETRIC MEASURING SYSTEM | | Art Unit To Be Assigned |
| | | Inventor(s) Pawel DRABAREK |

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

1. In accordance with the duty of disclosure under 37 C.F.R. § 1.56 and in conformance with the procedures of 37 C.F.R. §§ 1.97 and 1.98 and M.P.E.P. § 609, attorneys for Applicant hereby bring the following references to the attention of the Examiner. The references are listed on the attached modified PTO form 1449. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.
2. A copy of each patent, publication or other information listed on the modified PTO form 1449 is enclosed, except as otherwise indicated on the modified PTO form 1449.

Dated: 9/1/06

By: DR (A.N. 41077)
By: 8/2
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| INFORMATION DISCLOSURE STATEMENT BY APPLICANT PTO FORM 1449 | Atty. Docket No. 10191/4351 | Serial No. To Be Assigned |
| | Applicant(s) Pawel DRABAREK | |
| | Filing Date Herewith | Group To Be Assigned |

U. S. PATENT DOCUMENTS

| EXAMINER'S INITIALS | PATENT NUMBER | PATENT DATE | NAME | CLASS | SUBCLASS | FILING DATE |
|---------------------|---------------|---------------|---------------|-------|----------|-------------|
| | 4,770,535* | Sep. 13, 1988 | KIM et al. | | | |
| | 5,011,262* | Apr. 30, 1991 | LAYTON et al. | | | |
| | 5,442,720* | Aug. 15, 1995 | SHAW et al. | | | |

* Copy of reference is not enclosed because reference is cited in Search Report (copy of reference provided by International Searching Authority).

FOREIGN PATENT DOCUMENTS

| EXAMINER'S INITIALS | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUB-CLASS | TRANSLATION |
|---------------------|-----------------|--------------|---------|-------|-----------|-------------|
| | | | | | | YES NO |
| | 198 08 273*,** | Sep. 9, 1999 | Germany | | | |

* Copy of reference is not enclosed because reference is cited in Search Report (copy of reference provided by International Searching Authority).

** Described in the Specification.

OTHER DOCUMENTS

| EXAMINER'S INITIALS | AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC. | |
|---------------------|--|--|
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| EXAMINER | DATE CONSIDERED |
|---|-----------------|
| EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | |